

Supplementary Information

Directed migration of additives to form top interlayers in polymer light emitting diodes

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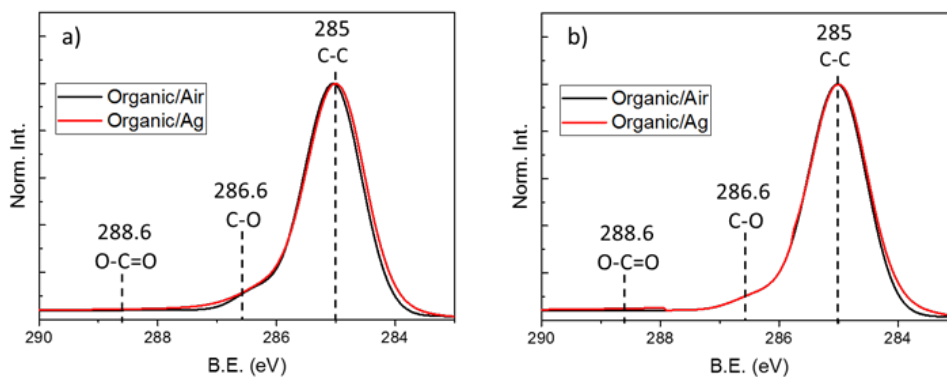


Figure S1. C1s XPS spectra of pristine F8BT (a) and F8BT with 0.75 mg/ml PEG (b) measured on the bare organic surface (black lines) and through ~3 nm Ag film (red line). The absence of traces at 286.6 eV in all spectra confirms that PEG does not migrate to the F8BT/Ag interface.

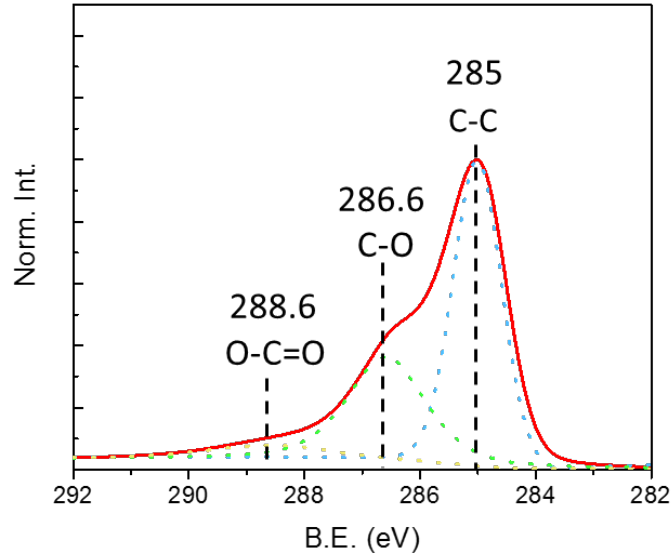


Figure S2. Deconvoluted C1s spectra of F8BT with 0.75 mg/ml PEG measured through ~3nm Al.

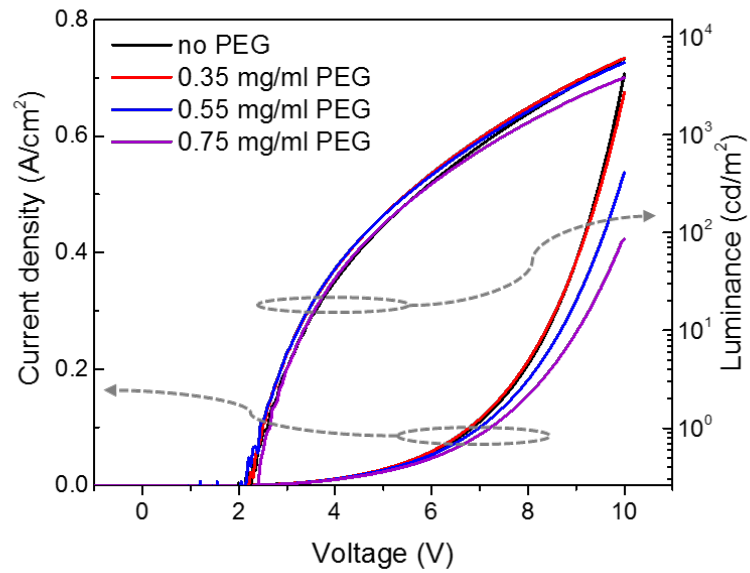


Figure S3. J-V-L characteristics of devices with SY that were annealed prior to Al deposition.